



**International
Standard**

ISO 20289

**Surface chemical analysis — Total
reflection X-ray fluorescence
analysis of water**

*Analyse chimique des surfaces — Analyse par fluorescence de
rayons X en réflexion totale d'eau*

**Second edition
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Foreword

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This document was prepared by Technical Committee ISO/TC 201, *Surface Chemical Analysis*, Subcommittee SC 10, *X-ray Reflectometry (XRR) and X-ray Fluorescence (XRF) Analysis*.

This second edition cancels and replaces the first edition (ISO 20289:2018) which has been technically revised.

The main changes are as follows:

- updated Clause 2 and bibliography;
- editorial changes and correction of verbal forms;
- revision of [Annex A](#) removing the use of relative uncertainty;

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